

Notice of References Cited		Application/Control No. 10/541,815	Applicant(s)/Patent Under Reexamination GERLT ET AL.	
		Examiner Matthew W. Such	Art Unit 2891	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,447,879	09-2002	Sakurai et al.	428/161
*	B US-6,958,270	10-2005	Misra et al.	438/257
*	C US-6,908,536	06-2005	Beckmann, Udo	204/412
*	D US-2004/0084080	05-2004	Sager et al.	136/263
*	E US-2003/0087533	05-2003	Stupp et al.	438/745
*	F US-5,942,388	08-1999	Willner et al.	435/6
*	G US-7,074,519	07-2006	Kuhr et al.	429/149
*	H US-6,300,141	10-2001	Segal et al.	435/287.1
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Roth, K.M., et al. "Characterization of Charge Storage in Redox-Active Self-Assembled Monolayers." LANGMUIR, Vol. 18 (2002): pp. 4030-4040.
V	Roth, K.M., et al. "Molecular Approaches Toward Information Storage Based on the Redox Properties of Porphyrins in Self-Assembled Monolayers." J. VAC. SCI. TECHNOL. B, Vol. 18, No. 5 (Sep/Oct 2000): pp. 2359-2364.
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.